Juan Carlos Barreiro earned his B.Sc. (honored with an Extraordinary Award) and his Ph. D. degrees in Physics from Universitat de València, Spain, in 1985 and 1992, respectively. He carried out research, as a postdoctoral research fellow, at INAOE, Puebla (México) and The Institute of Optics, University of Rochester (NY, U.S.A.). He is currently Associate Professor at the Department of Optics, Universitat de València. His current research interests include optical diffraction, high-resolution optical microscopy and integral imaging.